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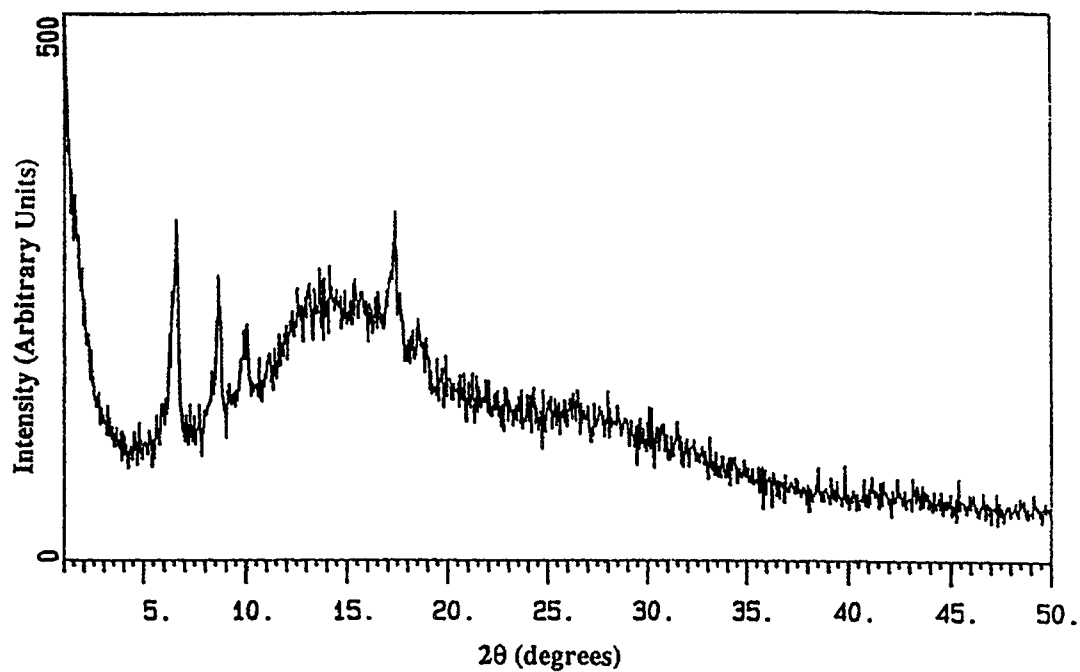
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Supporting Figure 4. X-ray powder diffraction pattern recorded for a thin film of 20 wt% [Bu₂Ph₂Tth]PF₆/PMMA.